Special Issue

Advanced Technologies for Testing, Diagnosis and Prognosis in Electronic Systems and Devices

Message from the Guest Editors

Whether it is complex electronic systems such as radars, communication systems, and mobile phones, or complex electronic devices such as IGBT, CPU, RAM, SOC, and Chiplet, the safe and reliable operation of systems is a primary concern. In recent years, with the development of microelectronics and artificial intelligence technology, advanced technologies associated with the testing, diagnosis, and prediction processes of electronic systems and devices have emerged. This Special Issue calls for papers on advanced technologies related to testing, diagnosis and prognosis in electronic systems and devices, such as radars, lithium batteries, and integrated circuits; these include, but are not limited to, test methods, health monitoring, fault feature extraction, diagnostic reasoning methods, performance degradation, life prediction, etc.

Guest Editors

Prof. Dr. Bing Long

School of Automation Engineering, University of Electronic Science and Technology of China (UESTC), Chengdu 611731, China

Prof. Dr. Yindong Xiao

School of Automation Engineering, University of Electronic Science and Technology of China, Chengdu 611731, China

Deadline for manuscript submissions

closed (20 September 2025)

Applied Sciences

an Open Access Journal by MDPI

Impact Factor 2.5
CiteScore 5.5

mdpi.com/si/197819

Applied Sciences
Editorial Office
MDPI, Grosspeteranlage 5
4052 Basel, Switzerland
Tel: +41 61 683 77 34
applsci@mdpi.com

mdpi.com/journal/applsci

Applied Sciences

an Open Access Journal by MDPI

Impact Factor 2.5
CiteScore 5.5

mdpi.com/journal/applsci

MDPI

About the Journal

Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal *Applied Sciences* has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo
Dipartimento di Fisica, Politecnico di Milano, Piazza L. da Vinci 32, 20133 Milano, Italy

Author Benefits

Open Access:

free for readers, with article processing charges (APC) paid by authors or their institutions.

High Visibility:

indexed within Scopus, SCIE (Web of Science), Ei Compendex, Inspec, CAPlus / SciFinder, and other databases.

Journal Rank:

JCR - Q2 (Engineering, Multidisciplinary) / CiteScore - Q1 (General Engineering)